| Notice of References Cited | Application/Control No. 10/681,269 | Applicant(s)/Patent Under Reexamination LEE ET AL. | |
|---|---|---|---|
| | Examiner Hai L. Nguyen | Art Unit 2816 | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|---|---|---|---|
| X | A | US-6,847,251 | 01-2005 | Kao, Hsueh-Wu | 327/536 |
| X | B | US-6,825,730 | 11-2004 | Sun, Runhua | 331/16 |
| X | C | US-6,771,102 | 08-2004 | Abidin et al. | 327/157 |
| X | D | US-6,686,794 | 02-2004 | Abidin et al. | 327/537 |
| X | E | US-6,385,265 | 05-2002 | Duffy et al. | 375/374 |
| X | F | US-6,275,097 | 08-2001 | Liang et al. | 327/536 |
| X | G | US-5,740,213 | 04-1998 | Dreyer, Stephen F. | 375/374 |
| X | H | US-5,736,880 | 04-1998 | Bruccoleri et al. | 327/157 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

**FOREIGN PATENT DOCUMENTS**

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|---|---|---|---|---|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

**NON-PATENT DOCUMENTS**

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.